



E-mail: sales@taipaq.cn

# Specification for Approval

		Date: 2019	/04/02	
	Custo	mer :		_
	TAI-TECH P/N:	ACM45TNV-	101TP02-D	
	CUSTOMER P/N:			
	DESCRIPTION:			
	QUANTITY:		pcs	
REM	IARK:			
	Cı	ıstomer Approval	Feedback	
西北臺慶科技股份有限公司 TAI-TECH Advanced Electro <u>Headquarter:</u> NO.1 YOU 4TH ROAD, YOUTH INDU TAO-YUAN HSIEN, TAIWAN, R.O.C. TEL: +886-3-4641148 FAX: +886-3 http://www.tai-tech.com.tw E-mail: sales@tai-tech.com.tw	STRIAL DISTRICT, YANG-N			
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慶邦電子元器件(泗洪)有限公	司		APPROVED	CHECKED
TAIPAQ ELECTRONICS (SIHOI Sihong development zone Suqian C TEL: +86-527-88601191 FAX: +86-5	NG) CO., LTD city, Jiangsu , CHINA.		担党中	罗伊虹

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楊祥忠	羅偉軒	何玉蓮
Mike Yang	Happy Lo	Anna Ho

# Wire Wound Type Common Mode Filter

ACM45TNV-101TP02-D

ECN HISTORY LIST											
REV	DATE	DESCRIPTION	APPROVED	CHECKED	DRAWN						
1.0	19/04/02	新發行	楊祥忠	羅偉軒	何玉蓮						
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# Wire Wound Type Common Mode Filter

ACM45TNV-101TP02-D

### 1. Features

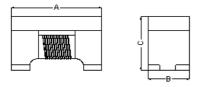
1. High common mode impedance at high frequency effects excellent noise suppression performance.

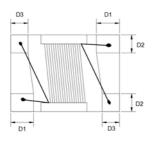
- 2. ACM45TNV series realizes small size and low profile.
- 3. 100% Lead(Pb) & Halogen-Free and RoHS compliant.
- 4. High reliability Reliability tests comply with AEC-Q200
- 5. Operating temperature -55~+150°C (Including self temperature rise)

### 2. Dimension

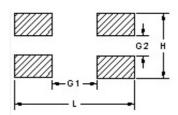








### **Recommended PC Board Pattern**



Series	A(mm)	B(mm)	C(mm)	D1(mm)	D2(mm)	D3(mm)	L(mm)	H(mm)	G1(mm)	G2(mm)
ACM45TNV	4.5±0.2	3.2±0.2	2.8±0.2	0.75±0.2	0.85±0.2	0.60±0.2	5.0	3.6	3.4	1.7

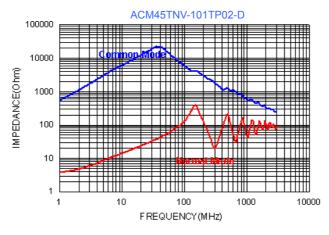
### 3. Part Numbering

<b>ACM</b>	<b>45</b>	T	N	V	-	101	TP	<b>02</b>	-	D
Α	В	С	D	Е		F	G	Н		I

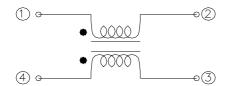
- A: Series
- B: Dimension
- C: Material
- D: Type N45
  E: Category Code V=Vehicle
  F: Inductance 101=100uH
  G: Packaging T=Taping and Reel
  H:Rated Current 02=230mA
- I: Control S/N

### 4. Specification

TAI-TECH Part Number	Impeda	on mode ance (Ω) //Hz]	Inductance ( µ H)+50/-30% [100kHz/0.1V]	DC Resistance $(\Omega)$ max.	Rated Current (mA)	Rated Volt. (Vdc)	IR (MΩ) min.
ACM45TNV-101TP02-D	2000 min.	5800 typ.	100	2.0	200	50	10

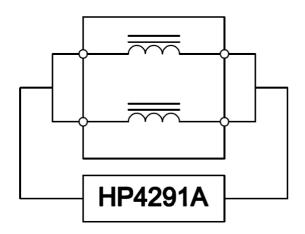


## 5. Schematic Diagram

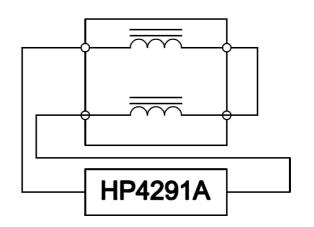


### **6. MEASURING CIRCUITS 2LINE**

## Common mode

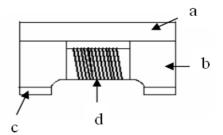


# Differential mode



### 7. Materials

No.	Description	Specification
a.	Upper Plate	Ferrite
b.	Core	Ferrite Core
С	Termination	Ag/Ni/Sn
d	Wire	Enameled Copper Wire



## 8. Reliability and Test Condition

Item	Performance	Test Condition				
Operating temperature	-55~+150℃ (Including self - temperature rise)					
Storage temperature	-55~+125°ℂ (on board)					
Electrical Performance Tes	st					
L(common mode)		Agilent-4291A+ Agilent -16197A				
DCR	Refer to standard electrical characteristics list.	Agilent-4338B				
I.R.		Agilent4339				
Temperature Rise Test	Rated Current < 1A ΔT 20°C Max Rated Current ≥ 1A ΔT 40°C Max	1.Applied the allowed DC current.     2.Temperature measured by digital surface thermometer				
Reliability Test						
High Temperature Exposure(Storage) AEC-Q200  Temperature Cycling AEC-Q200		Preconditioning: Run through IR reflow for 2 times.( IPC/JEDEC J-STD-020DClassification Reflow Profiles  Temperature: 150±2°C  Duration: 1000hrs Min.  Measured at room temperature after placing for 24±2 hrs  Preconditioning: Run through IR reflow for 2 times.( IPC/JEDEC J-STD-020DClassification Reflow Profiles  Condition for 1 cycle  Step1: -55±2°C 30min Min.  Step2: 150±2°C transition time 1min MAX.  Step3: 150±2°C 30min Min.  Step4: Low temp. transition time 1min MAX.  Number of cycles: 1000  Measured at room temperature after placing for 24±2 hrs				
Moisture Resistance	Appearance: No damage. Impedance: within±15% of initial value Inductance: within±10% of initial value Q: Shall not exceed the specification value. RDC: within ±15% of initial value and shall not exceed the specification value	Preconditioning: Run through IR reflow for 2 times.( IPC/JEDEC J-STD-020DClassification Reflow Profiles 1.Baked at50°C for 25hrs, measured at room temperature after placing for 4 hrs.  2.Raise temperature to 65±2°C 90-100%RH in 2.5hrs, and keep 3 hours, cool down to 25°C in 2.5hrs.  3.Raise temperature to 65±2°C 90-100%RH in 2.5hrs, and keep 3 hours, cool down to 25°C in 2.5hrs, keep at 25°C for 2hrs then keep at -10°C for 3hrs  4.Keep at 25°C 80-100%RH for 15min and vibrate at the frequency of 10 to 55 Hz to 10 Hz, measure at room temperature after placing for 1-2 hrs.				
Biased Humidity (AEC-Q200)		Preconditioning: Run through IR reflow for 2 times.( IPC/JEDEC J-STD-020DClassification Reflow Profiles Humidity: 85±3*R.H, Temperature: 85°C±2°C Duration: 1000hrs Min				
High Temperature Operational Life (AEC-Q200)		Measured at room temperature after placing for24±2hrs Preconditioning: Run through IR reflow for 2 times.( IPC/JEDEC J-STD-020DClassification Reflow Profiles Temperature: 150±2°C Duration: 1000hrs Min. with 100% rated current. Measured at room temperature after placing for24±2hrs				
External Visual	Appearance : No damage.	Inspect device construction, marking and workmanship. Electrical Test not required.				
Physical Dimension	According to the product specification size measurement	According to the product specification size measurement				
Resistance to Solvents	Appearance: No damage.	Add aqueous wash chemical - OKEM clean or equivalent.				
Mechanical Shock	Appearance: No damage. Impedance: within±15% of initial value Inductance: within±10% of initial value Q: Shall not exceed the specification value. RDC: within ±15% of initial value and shall not exceed the specification value	Type Peak value (g's) Normal duration (D) (ms) Form change (Vi)ft/sec SMD 100 6 Half-sine 12.3  Lead 100 6 Half-sine 12.3  shocks in each direction along 3 perpendicular axes.				

Item	Performance	Test Condition				
Vibration		IPC/JEDEC J-STD-020DClassification Reflow Profiles Oscillation Frequency: 10~2K~10Hz for 20 minute Equipment: Vibration checker Total Amplitude:1.52mm±10% Testing Time: 12 hours(20 minutes, 12 cycles each of 3 orientations) ∘  Test condition:				
Resistance to Soldering Heat	Appearance: No damage. Impedance: within±15% of initial value Inductance: within±10% of initial value Q: Shall not exceed the specification value. RDC: within ±15% of initial value and shall not exceed the specification value	Temperature (°C) Time(s) Temperature ramp/immersion and emersion rate Number of heat cycles  260±5(solder temp) 10±1 25mm/s ±6 mm/s 1				
Thermal shock (AEC-Q200)		Preconditioning: Run through IR reflow for 2 times.( IPC/JEDEC J-STD-020DClassification Reflow Profiles Condition for 1 cycle Step1: -55±2°C 15±1min Step2: 150±2°C within 20Sec. Step3: 150±2°C 15±1min Number of cycles: 300 Measured at room fempraturc after placing fo24±2hrs				
ESD	Appearance : No damage.	to to the total to				
Solderability	More than 95% of the terminal electrode should be covered with solder •	a. Method B, 4 hrs @155°C dry heat @235°C±5°C b. Method B @ 215°C±5°C category 3.(8hours ± 15 min) c. Method D category 3. (8hours ± 15 min)@ 260°C±°C Preheat: 150°C,60sec. Solder: Sn96.5% Ag3% Cu0. 5% Temperature: 245±5°C ∘ Flux for lead free: Rosin. 9.5% ∘ Dip time: 4±1sec. Depth: completely cover the termination				
Electrical Characterization	Refer Specification for Approval	Summary to show Min, Max, Mean and Standard deviation .				
Flammability	Electrical Test not required.	V-0 or V-1 are acceptable.				
Board Flex	Appearance : No damage	Preconditioning: Run through IR reflow for 2 times.( IPC/JEDEC J-STD-020DClassification Reflow Profiles Place the 100mm X 40mm board into a fixture similar to the one shown in below Figure with the component facing down. The apparatus shall consist of mechanical means to apply a force which will bend the board (D) X = 2 mm minimum. The duration of the applied forces shall be 60 (+ 5) sec. The force is to be applied only once to the board.  Support  Solder Chip Printed circuit board before testing  Probe to exert bending force  Radius 340  Probe to exert bending force				
Terminal Strength(SMD)	Appearance : No damage  www.tai-tech.com.t	Preconditioning: Run through IR reflow for 2 times.( IPC/JEDEC J-STD-020D Classification Reflow Profiles With the component mounted on a PCB with the device to be tested, apply a 17.7 N (1.8 Kg) force to the side of a device being tested. This force shall be applied for 60 +1 seconds. Also the force shall be applied gradually as not to apply a shock to the component being tested.  radius 0,5 mm  DUT  wide  thickness sheat force				

## 9. Soldering and Mounting

#### 9-1. Soldering

Mildly activated rosin fluxes are preferred. TAI-TECH terminations are suitable for all wave and re-flow soldering systems. If hand soldering cannot be avoided, the preferred technique is the utilization of hot air soldering tools.

#### 9-1.1 Solder re-flow:

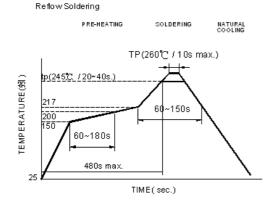
Recommended temperature profiles for re-flow soldering in Figure 1.

#### 9-1.2 Soldering Iron(Figure 2):

Products attachment with a soldering iron is discouraged due to the inherent process control limitations. In the event that a soldering iron must be employed the following precautions are recommended.

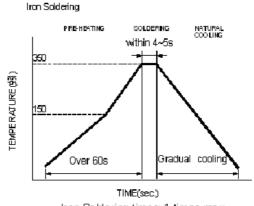
- • Never contact the ceramic with the iron tip • Use a 20 watt soldering iron with tip diameter of 1.0mm
- 1.0mm tip diameter (max) • 350°C tip temperature (max)

• Limit soldering time to 4~5 sec.



Reflow times: 3 times max.

Fig.1

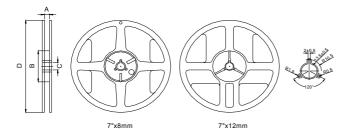


Iron Soldering times: 1 times max.

Fig.2

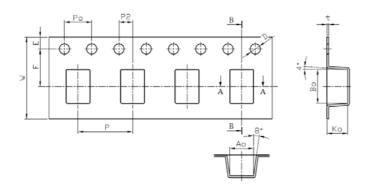
### 10. Packaging Information

#### 10-1. Reel Dimension



Туре	A(mm)	B(mm)	C(mm)	D(mm)	
7"x12mm	13.5±0.5	60±2	13.5±0.5	178±2	

#### 10-2. Tape Dimension / 12mm

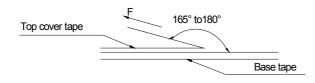


	Series	P(mm)	Po(mm)	P2(mm)	Bo(mm)	Ao(mm)	Ko(mm)	D(mm)	E(mm)	F(mm)	W(mm)	t(mm)
ſ	ACM45TNV	8.00±0.10	4.00±0.10	2.00±0.05	4.90±0.10	3.60±0.10	3.00±0.10	1.05+0.10/-0.00	1.75±0.10	5.50±0.05	12.00±0.10	0.26±0.05

### 10-3. Packaging Quantity

Chip size	Chip/Reel	Inner Box	Middle Box	Carton
ACM45TNV	500	2000	10000	20000

### 10-4. Tearing Off Force



The force for tearing off cover tape is 15 to 80 grams in the arrow direction under the following conditions.

Room Temp.	Room Humidity	Room atm	Tearing Speed	
(℃)	(%)	(hPa)	mm/min	
5~35	45~85	860~1060	300	

### **Application Notice**

• Storage Conditions(component level)

To maintain the solderability of terminal electrodes:

- 1. TAI-TECH products meet IPC/JEDEC J-STD-020D standard-MSL, level 1.
- 3. Recommended products should be used within 12 months form the time of delivery.
- 4. The packaging material should be kept where no chlorine or sulfur exists in the air.
- Transportation
  - 1. Products should be handled with care to avoid damage or contamination from perspiration and skin oils.
  - 2. The use of tweezers or vacuum pick up is strongly recommended for individual components.
  - 3. Bulk handling should ensure that abrasion and mechanical shock are minimized.



# **Test Report**

號碼(No.): CE/2019/33002

日期(Date): 2019/03/19

頁數(Page): 1 of 14

西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.

(臺慶精密電子(昆山)有限公司 / TAI-TECH ADVANCED ELECTRONICS (KUN-SHAN) CO., LTD.)

(慶邦電子元器件 (泗洪) 有限公司 / TAIPAQ ELECTRONICS (SI-HONG) CO., LTD.)

桃園市楊梅區幼獅工業區幼四路1號 (NO. 1, YOU 4TH ROAD, YOUTH INDUSTRIAL DISTRICT, YANG-MEI, TAO-YUAN CITY, TAIWAN, R. O. C.)

(江蘇省昆山市篷朗昆嘉高科技工業區郭澤路 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA) (中國,江蘇省,宿遷市,泗洪縣,經濟開發區杭州路南側,建設北路東側 / THE SOUTH HANGZHOU ROAD AND THE EAST JIANSHE ROAD , ECONOMIC DEVELOPMENT ZONE , SIHONG COUNTY , SUQIANCITY , JIANGSU PROVINCE , P, R , CHINA)

以下測試樣品係由申請廠商所提供及確認 (The following sample(s) was/were submitted and identified by/on behalf of the applicant as):

樣品名稱(Sample Description)

WIREWOUND SERIES

樣品型號(Style/Item No.)

WCM · WCL · HSF · HDMI · DVI · BCM · PCM · TCM · LCM · LPF · TXF · ACM · DCM ·

WIH · BPH · TNH · YCM · STF · APO · TLM · SWFS SERIES

收件日期(Sample Receiving Date)

2019/03/13

測試期間(Testing Period)

2019/03/13 to 2019/03/19

測試結果(Test Results) :

請參閱下一頁 (Please refer to following pages).



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**Test Report** 

號碼(No.); CE/2019/33002

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頁數(Page): 2 of 14

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### 測試結果(Test Results)

測試部位(PART NAME)No.1

整體混測 (MIXED ALL PARTS)

測試項目 (Test Items)	單位 (Unit)	测試方法 (Method)	方法偵測 極限値 (MDL)	結果 (Result) No.1
鎬 / Cadmium (Cd)	mg/kg	参考IEC 62321-5 (2013),以感應耦合電 浆原子發射光譜儀檢測. / With	2	n. d.
鉛 / Lead (Pb)	mg/kg	reference to IEC 62321-5 (2013) and performed by ICP-AES.	2	n. d.
汞 / Mercury (Hg)	mg/kg	参考IEC 62321-4:2013+AMD1:2017,以感 應耦合電漿原子發射光譜儀檢測. / With reference to IEC 62321- 4:2013+AMD1:2017 and performed by ICP-AES.	2	n. d.
六價鉻 / Hexavalent Chromium Cr(VI)	mg/kg	参考IEC 62321-7-2 (2017),以UV-VIS檢 測. / With reference to IEC 62321-7- 2 (2017) and performed by UV-VIS.	8	n. d.
多溴聯苯總和 / Sum of PBBs	mg/kg			n. d.
一溴聯苯 / Monobromobiphenyl	mg/kg		5	n, d,
二溴聯苯 / Dibromobiphenyl	mg/kg	參考IEC 62321-6 (2015),以氣相層析儀	5	n. d.
三溴聯苯 / Tribromobiphenyl	mg/kg		5	n. d.
四溴聯苯 / Tetrabromobiphenyl	mg/kg		5	n. d.
五溴聯苯 / Pentabromobiphenyl	mg/kg	/質譜儀檢測. / With reference to IEC	5	n. d.
六溴聯苯 / Hexabromobiphenyl	mg/kg	62321-6 (2015) and performed by GC/MS.	5	n. d.
七溴聯苯 / Heptabromobiphenyl	mg/kg		5	n. d.
八溴聯苯 / Octabromobiphenyl	mg/kg		5	n. d.
九溴聯苯 / Nonabromobiphenyl	mg/kg	]	5	n. d.
十溴聯苯 / Decabromobiphenyl	mg/kg	]	5	n. d.

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測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限値 (MDL)	結果 (Result) No.1
多溴聯苯醚總和 / Sum of PBDEs	mg/kg		<del>-</del>	n. d.
一溴聯苯醚 / Monobromodiphenyl ether	mg/kg		5	n. d.
二溴聯苯醚 / Dibromodiphenyl ether	mg/kg	[	5	n. d.
三溴聯苯醚 / Tribromodiphenyl ether	mg/kg		5	n. d.
四溴聯苯醚 / Tetrabromodiphenyl ether	mg/kg	參考 IEC 62321-6 (2015),以氣相層析儀	5	n. d.
五溴聯苯醚 / Pentabromodiphenyl ether	mg/kg	/質譜儀檢測. / With reference to IEC 62321-6 (2015) and performed by	5	n. d.
六溴聯苯醚 / Hexabromodiphenyl ether	mg/kg	GC/MS.	5	n, d.
七溴聯苯醚 / Heptabromodiphenyl ether	mg/kg	007 mg.	5	n. d.
八溴聯苯醚 / Octabromodiphenyl ether	mg/kg		5	n. d.
九溴聯苯醚 / Nonabromodiphenyl ether	mg/kg		5	n. d.
十溴聯苯醚 / Decabromodiphenyl ether	mg/kg		5	n. d.
鹵素 / Halogen				
鹵素(氟)/ Halogen-Fluorine (F) (CAS No.: 14762-94-8)	mg/kg		50	n. d.
鹵素 (氣) / Halogen-Chlorine (C1) (CAS No.: 22537-15-1)	mg/kg	参考BS EN 14582 (2016),以離子層析儀 分析. / With reference to BS EN 14582 (2016). Analysis was performed by IC.	50	n. d.
鹵素(溴)/ Halogen-Bromine (Br) (CAS No.: 10097-32-2)	mg/kg		50	n. d.
鹵素 (碘) / Halogen-Iodine (I) (CAS No.: 14362-44-8)	mg/kg		50	n. d.
全氟辛烷磺酸 / Perfluorooctane sulfonates (PFOS-Acid, Metal Salt, Amide)	mg/kg	参考US EPA 3550C (2007),以液相層析 儀/質譜儀檢測. / With reference to US EPA 3550C (2007). Analysis was	10	n, d,
全氟辛酸 / PFOA (CAS No.: 335-67-1)	mg/kg	performed by LC/MS.	10	n. d.
聚氯乙烯 / PVC	**	以紅外光譜分析及焰色法檢測. / Analysis was performed by FTIR and FLAME Test.	_	Negative

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測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法侦测 極限値 (MDL)	結果 (Result) No.1
鄰苯二甲酸二 (2-乙基己基)酯 / DEHP (Di- (2-ethylhexyl) phthalate) (CAS No.: 117-81-7)	mg/kg		50	n. d.
鄰苯二甲酸丁苯甲酯 / BBP (Butyl Benzyl phthalate) (CAS No.: 85-68-7)	mg/kg		50	n. d.
鄰苯二甲酸二丁酯 / DBP (Dibutyl phthalate) (CAS No.: 84-74-2)	mg/kg		50	n. d.
鄭苯二甲酸二異丁酯 / DIBP (Di-isobutyl phthalate) (CAS No.: 84-69-5)	mg/kg		50	n. d.
鄰苯二甲酸二異癸酯 / DIDP (Di- isodecyl phthalate) (CAS No.: 26761- 40-0; 68515-49-1)	mg/kg	參考IEC 62321-8 (2017),以氣相層析儀 /質譜儀檢測. / With reference to IEC 62321-8 (2017). Analysis was performed by GC/MS.	50	n, d.
鄰苯二甲酸二異壬酯 / DINP (Di- isononyl phthalate) (CAS No.: 28553- 12-0; 68515-48-0)	mg/kg	performed by Ge/MG.	50	n. d.
鄭苯二甲酸二正辛酯 / DNOP (Di-n-octyl phthalate) (CAS No.: 117-84-0)	mg/kg		50	n. d.
鄰苯二甲酸二正己酯 / DNHP (Di-n-hexyl phthalate) (CAS No.: 84-75-3)	mg/kg		50	n. d.
鄰苯二甲酸二戊酯 / DNPP (Di-n-pentyl phthalate) (CAS No.: 131-18-0)	mg/kg		50	n. d.
六溴環十二烷及所有主要被辨別出的異構物/Hexabromocyclododecane (HBCDD) and all major diastereoisomers identified ( $\alpha$ - HBCDD, $\beta$ - HBCDD, $\gamma$ - HBCDD) (CAS No.: 25637-99-4 and 3194-55-6 (134237-51-7, 134237-50-6, 134237-52-8))	mg/kg ·	参考IEC 62321 (2008),以氣相層析儀/ 質譜儀檢測. / With reference to IEC 62321 (2008). Analysis was performed by GC/MS.	5	n. d.

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測試項目 (Test Items)	單位 (Unit)	测試方法 (Method)	方法偵測 極限値 (MDL)	結果 (Result) No.1
銯 / Antimony (Sb)	mg/kg	參考US EPA 3052 (1996),以感應耦合電 漿原子發射光譜儀檢測. / With reference to US EPA 3052 (1996). Analysis was performed by ICP-AES.	2	n. d.
皴 / Beryllium (Be)	mg/kg	参考US EPA 3052 (1996),以感應耦合電 漿原子發射光譜儀檢測. / With reference to US EPA 3052 (1996). Analysis was performed by ICP-AES.	2	n. d.

### 備註(Note):

- 1. mg/kg = ppm : 0.1wt% = 1000ppm
- 2. n.d. = Not Detected (未檢出)
- 3. MDL = Method Detection Limit (方法偵測極限值)
- 4. "-" = Not Regulated (無規格值)
- 5. \*\*= Qualitative analysis (No Unit) 定性分析(無單位)
- 6. Negative = Undetectable 陰性(未偵測到); Positive = Detectable 陽性(已偵測到)
- 7. 樣品的測試是基於申請人要求混合測試,報告中的混合測試結果不代表其中個別單一材質的含量. (The samples was/were analyzed on behalf of the applicant as mixing sample in one testing. The above results was/were only given as the informality value.)

### PFOS参考資訊(Reference Information): 持久性有機污染物 POPs - (EU) 757/2010

PFOS濃度在物質或製備中不得超過0,001%(10ppm),在半成品、成品或零部件中不得超過0.1%(1000ppm),在紡織品或 塗層材料中不得超過1µg/m²。

(Outlawing PFOS as substances or preparations in concentrations above 0.001% (10ppm), in semi-finished products or articles or parts at a level above 0.1%(1000ppm), in textiles or other coated materials above 1µg/m<sup>2</sup>.)

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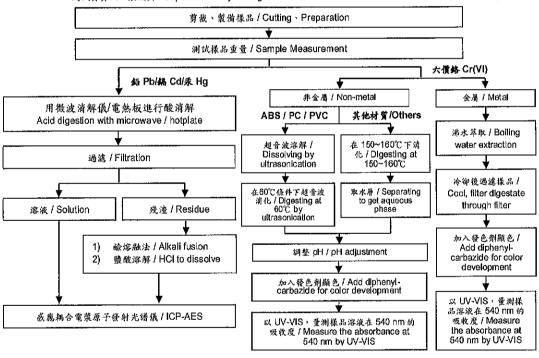
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### 重金屬流程圖 / Analytical flow chart of Heavy Metal

根據以下的流程圖之條件,樣品已完全溶解。(六價銘測試方法除外)

These samples were dissolved totally by pre-conditioning method according to below flow chart. (Cr<sup>6+</sup> test method excluded)

- 測試人員:陳思臻 / Technician : Rita Chen
- 测試負責人:張啟興 / Supervisor: Troy Chang



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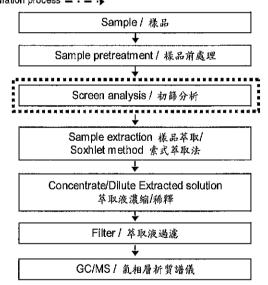
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### 多溴聯苯/多溴聯苯醚分析流程圖 / Analytical flow chart - PBB/PBDE

测試人員: 涂雅苓 / Technician: Yaling Tu

測試負責人:張啟興 / Supervisor: Troy Chang

初次測試程序 / First testing process -選择性篩檢程序 / Optional screen process \*\*\*\*\*\*\*\* 確認程序 / Confirmation process - · - · ▶



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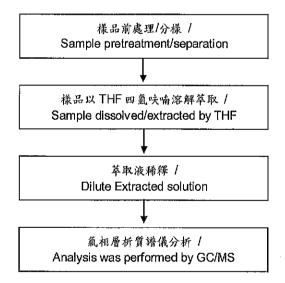
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#### 可塑劑分析流程圖 / Analytical flow chart - Phthalate

測試人員:涂雅苓 / Technician: Yaling Tu

測試負責人:張啟興 / Supervisor: Troy Chang

【测試方法/Test method: IEC 62321-8】



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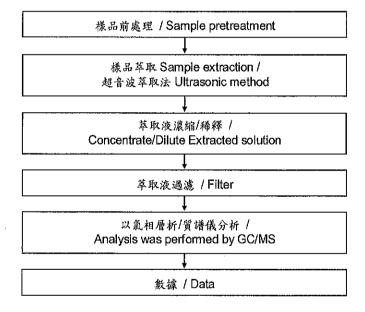
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### 六溴環十二烷分析流程圖 / Analytical flow chart - HBCDD

- 測試人員:涂雅苓 / Technician: Yaling Tu
- 測試負責人:張啟興 / Supervisor: Troy Chang



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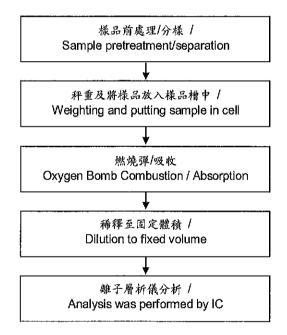
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#### 鹵素分析流程圖 / Analytical flow chart - Halogen

- 測試人員:陳恩臻 / Technician: Rita Chen
- 測試負責人:張啟興 / Supervisor: Troy Chang



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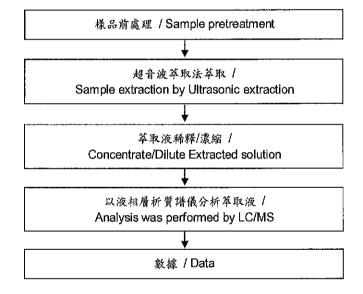
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### 全氟辛酸/全氟辛烷磺酸分析流程圖 / Analytical flow chart - PFOA/PFOS

- 測試人員:涂雅苓 / Technician: Yaling Tu
- 測試負責人:張啟興 / Supervisor: Troy Chang



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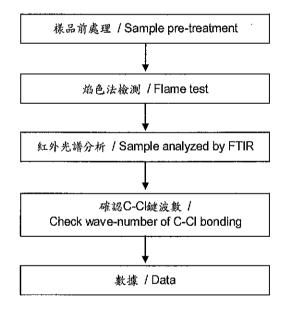
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(江蘇省昆山市篷朗昆嘉高科技工業區郭澤路 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA) (中國,江蘇省,宿遷市,泗洪縣,經濟開發區杭州路南側,建設北路東側 / THE SOUTH HANGZHOU ROAD AND THE EAST JIANSHE ROAD, ECONOMIC DEVELOPMENT ZONE, SIHONG COUNTY, SUQIANCITY, JIANGSU PROVINCE, P, R, CHINA)

### 聚氯乙烯物質判定分析流程圖 / Analysis flow chart - PVC

- 測試人員:涂雅苓 / Technician: Yaling Tu
- 測試負責人:張啟興 / Supervisor: Troy Chang



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# **Test Report**

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日期(Date): 2019/03/19

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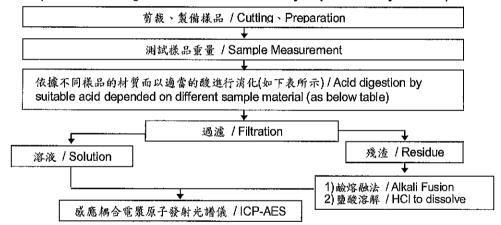
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> 根據以下的流程圖之條件,樣品已完全溶解。 / These samples were dissolved totally by pre-conditioning method according to below flow chart.

- 測試人員: 陳恩臻 / Technician: Rita Chen
- 測試負責人:張啟興 / Supervisor: Troy Chang

### 元素以 ICP-AES 分析的消化流程圖 (Flow Chart of digestion for the elements analysis performed by ICP-AES)



鋼,銅,鋁,焊錫 / Steel, copper, aluminum, solder	王水,硝酸,鹽酸,氫氯酸,雙氧水 / Aqua regia, HNO <sub>3</sub> , HCl, HF, H <sub>2</sub> O <sub>2</sub>
玻璃 / Glass	硝酸,氫氟酸 / HNO <sub>3</sub> /HF
金,鉤,鉋,陶瓷 / Gold, platinum, palladium, ceramic	王水 / Aqua regia
銀 / Silver	硝酸 / HNO <sub>3</sub>
塑膠 / Plastic	硫酸,雙氧水,硝酸,鹽酸 / H <sub>2</sub> SO <sub>4</sub> , H <sub>2</sub> O <sub>2</sub> , HNO <sub>3</sub> , HCl
其他 / Others	加入適當的試劑至完全溶解 / Added appropriate reagent to total digestion

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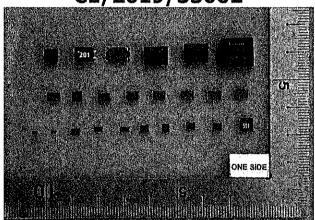
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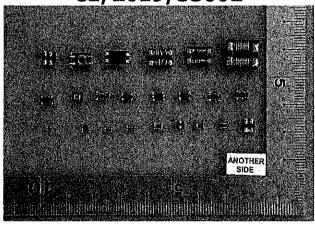
\* 照片中如有箭頭標示,則表示為實際檢測之樣品/部位。\*

(The tested sample / part is marked by an arrow if it's shown on the photo.)

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\*\* 報告結尾 (End of Report) \*\*

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